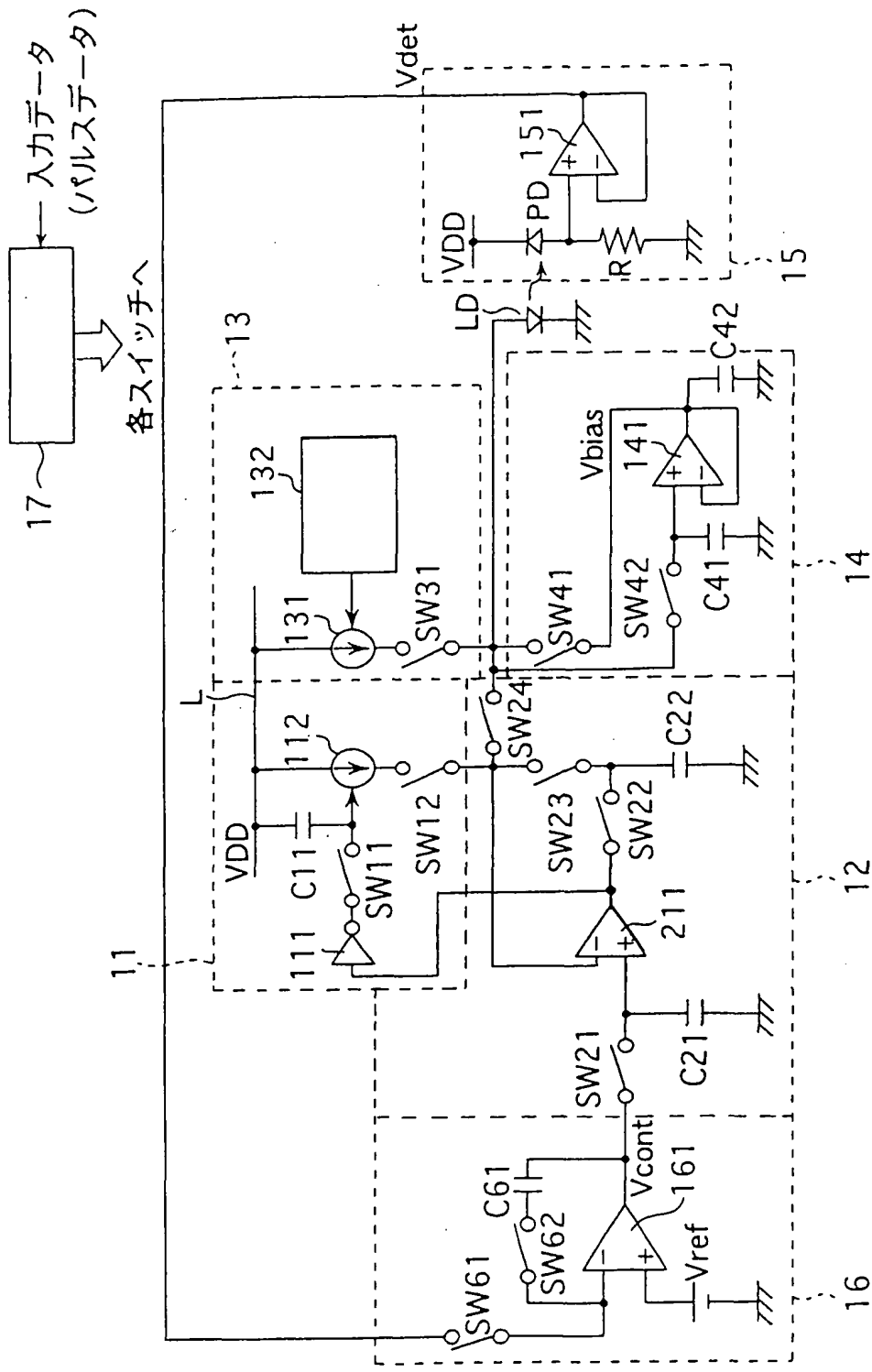


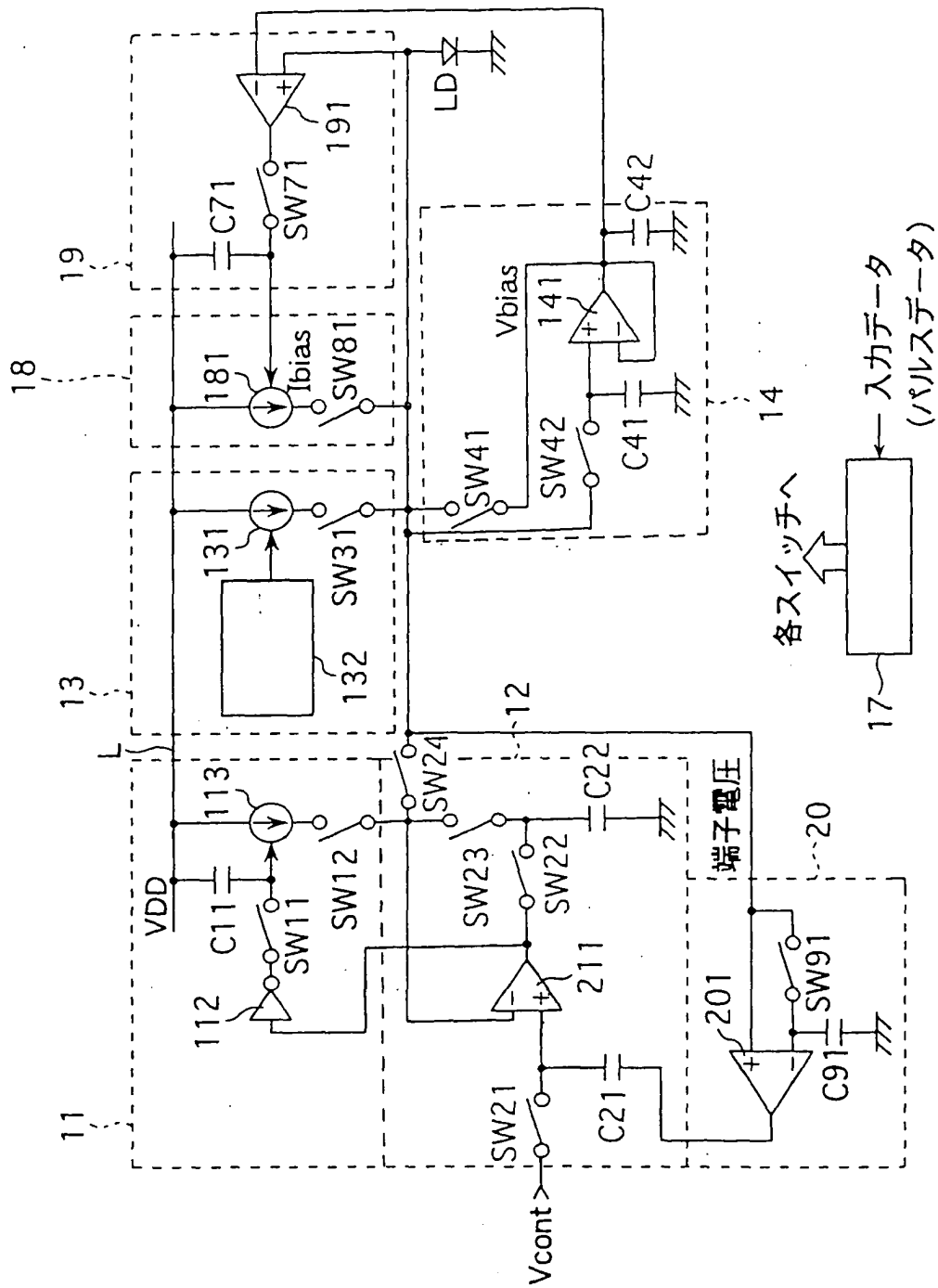
Fig. 1



[FIG. 1]
 132: TEST CURRENT SETTING PORTION
 17: CONTROL CIRCUIT
 INPUT DATA (PULSE DATA)
 TO RESPECTIVE SWITCHES

132: TEST CURRENT SETTING PORTION
17: CONTROL CIRCUIT
INPUT DATA (PULSE DATA)
TO RESPECTIVE SWITCHES

Fig. 4



[FIG. 4]
 132: TEST CURRENT SETTING PORTION
 17: CONTROL CIRCUIT
 INPUT DATA (PULSE DATA)
 TO RESPECTIVE SWITCHES
 TERMINAL VOLTAGE

Fig. 5

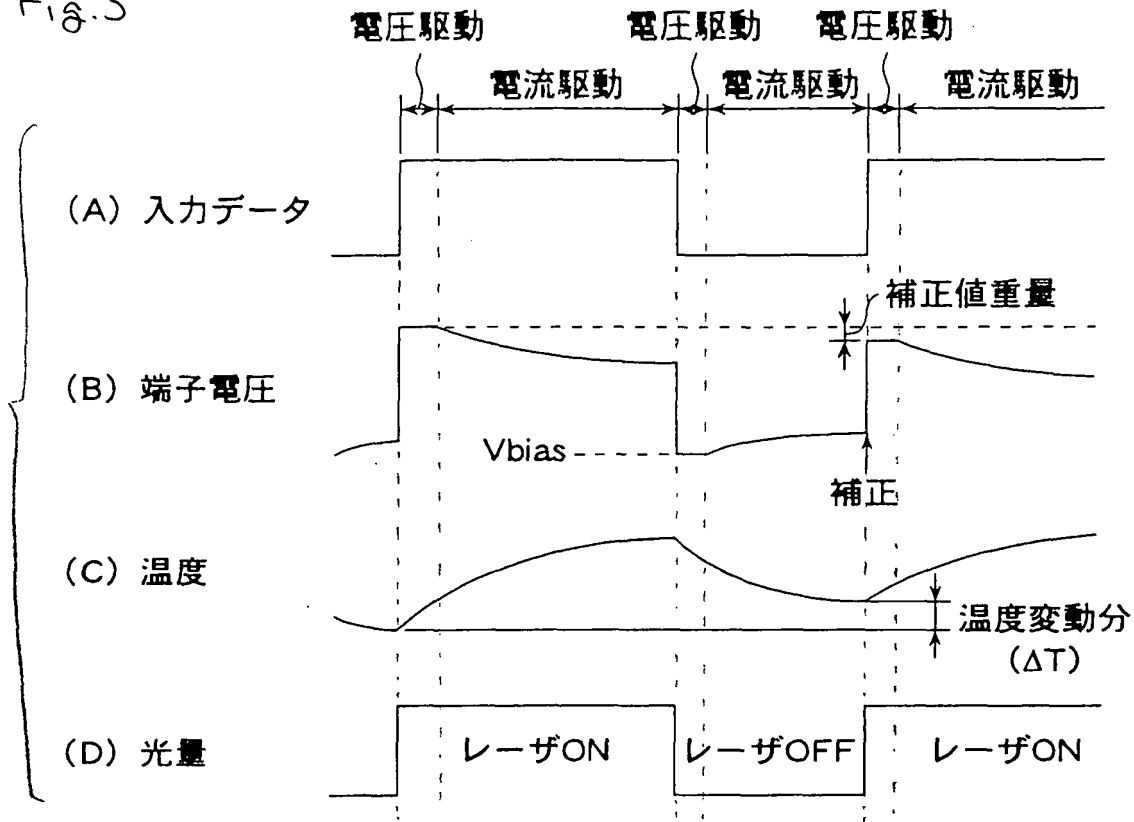
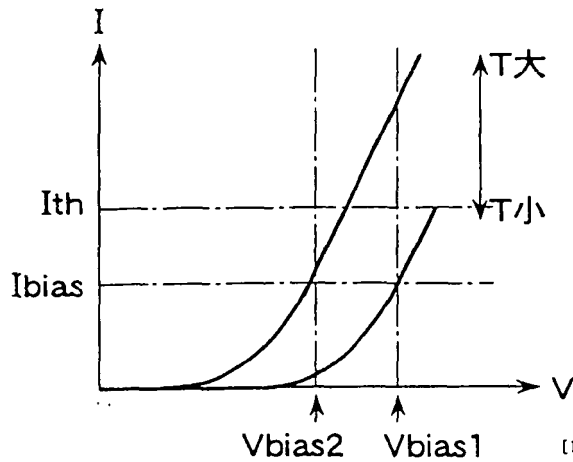


Fig. 6



[FIG. 5]

A: INPUT DATA
 VOLTAGE DRIVE
 CURRENT DRIVE
 B: TERMINAL VOLTAGE
 CORRECTION VALUE SUPERPOSITION
 CORRECTION
 C: TEMPERATURE
 TEMPERATURE CHANGE (ΔT)
 D: LIGHT INTENSITY
 LASER ON
 LASER OFF

[FIG. 6]

T HIGH
 T LOW

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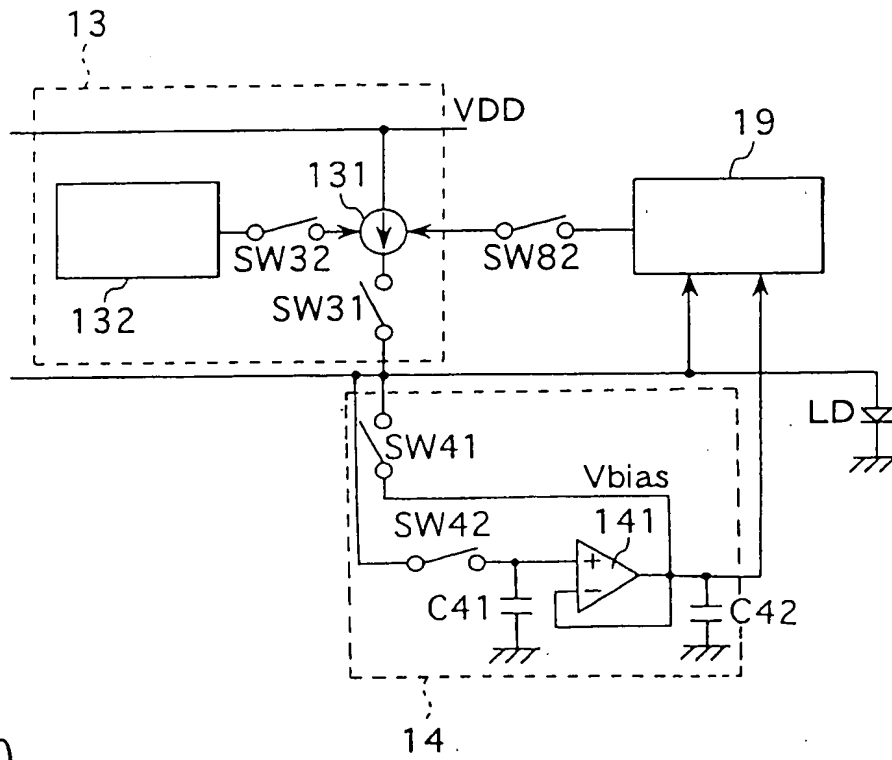
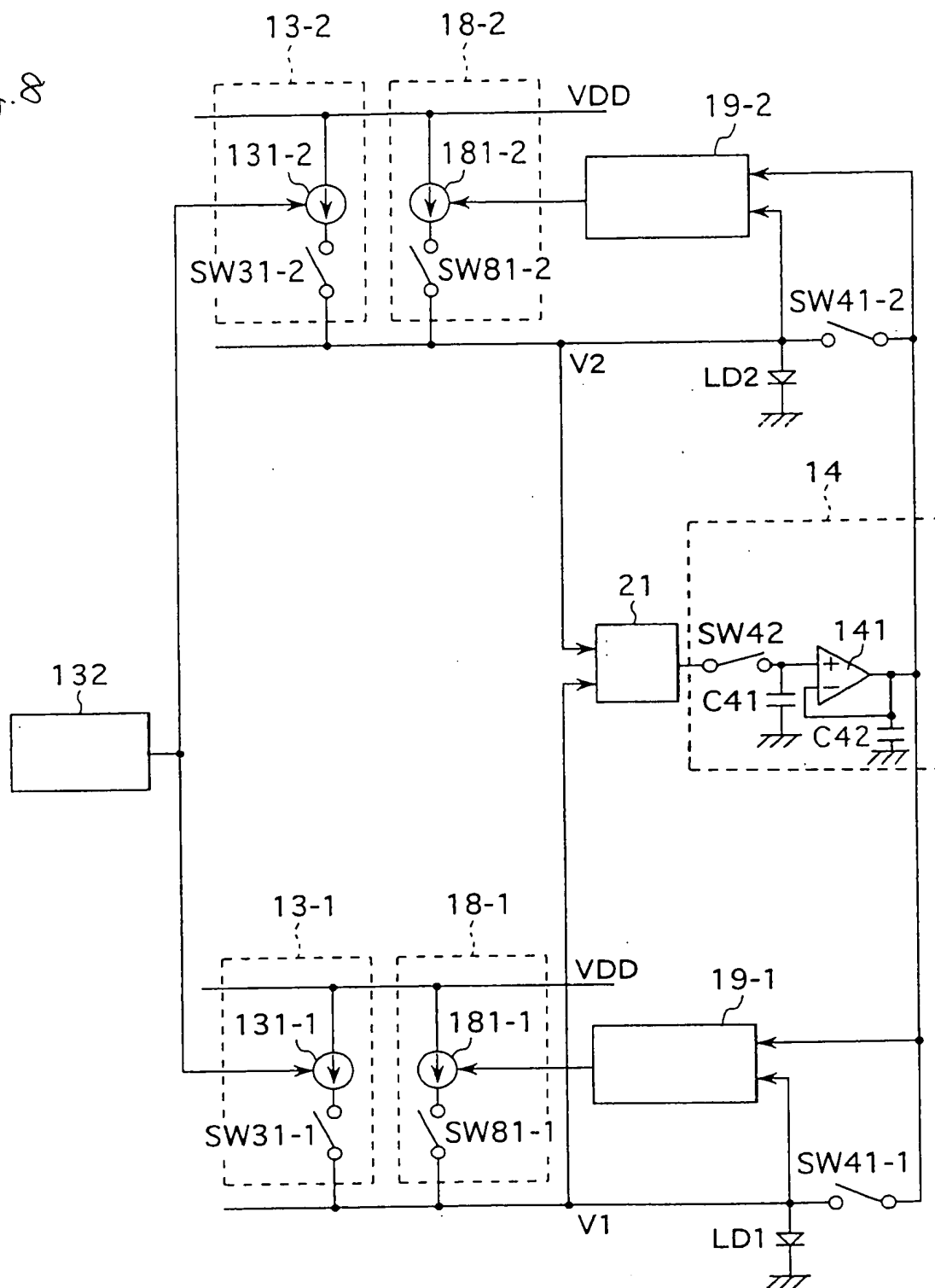


Fig. 7

[FIG. 7]

132: TEST CURRENT SETTING PORTION
19: BIAS CURRENT SETTING PORTION

Fig. 8

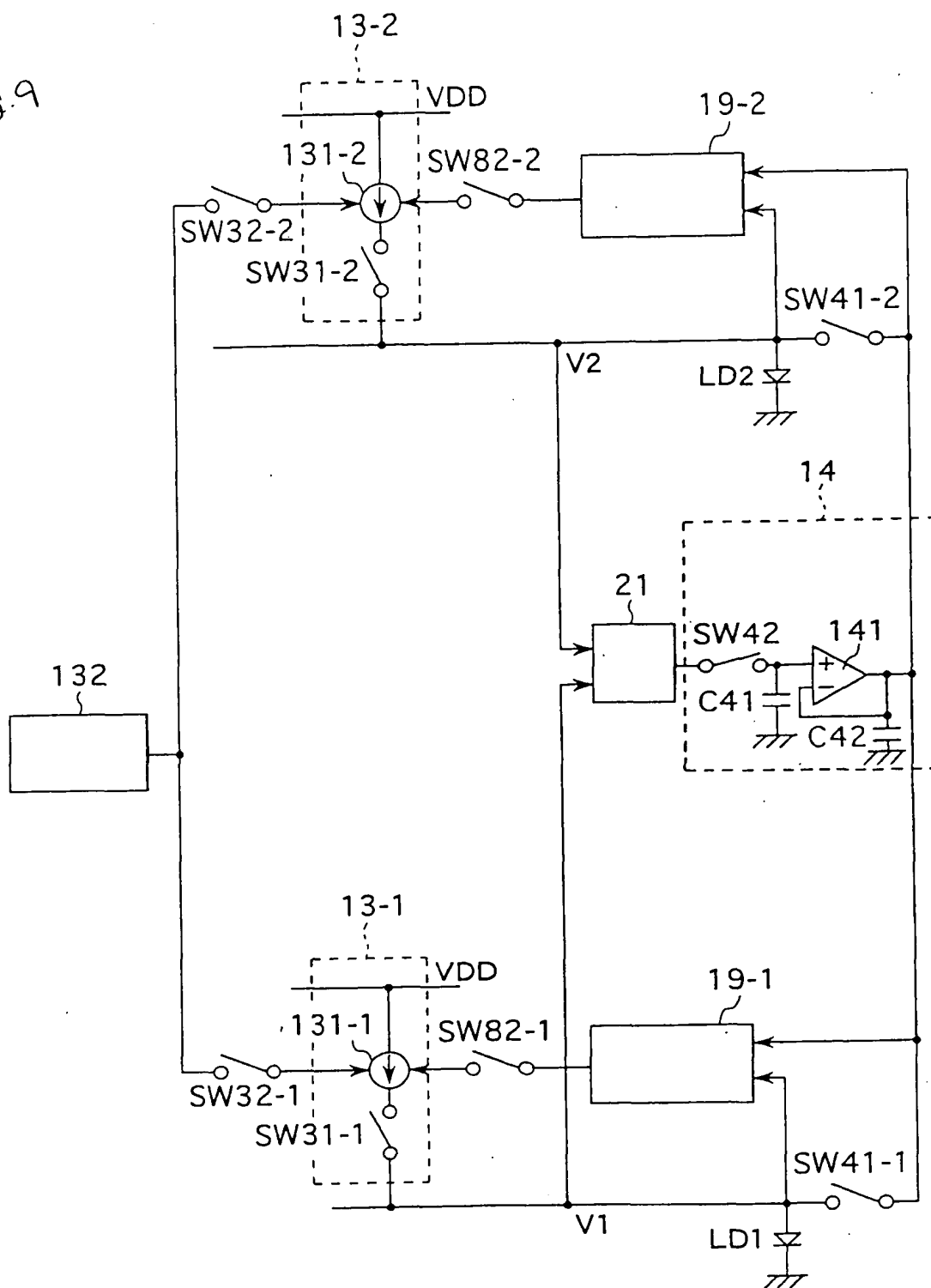


[FIG. 8]

132: TEST CURRENT SETTING PORTION
 19-1: BIAS CURRENT SETTING PORTION
 19-2: BIAS CURRENT SETTING PORTION
 21: ARITHMETIC CIRCUIT

Fig. 9

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[FIG. 9]

132: TEST CURRENT SETTING PORTION
 19-1: BIAS CURRENT SETTING PORTION
 19-2: BIAS CURRENT SETTING PORTION
 21: ARITHMETIC CIRCUIT

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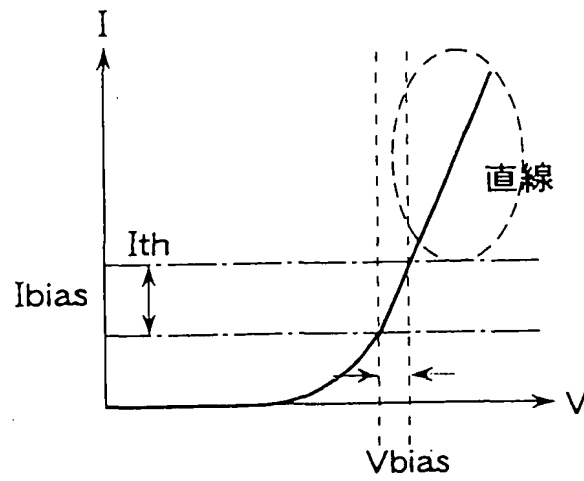


Fig. 11

[FIG. 11]
LINEAR